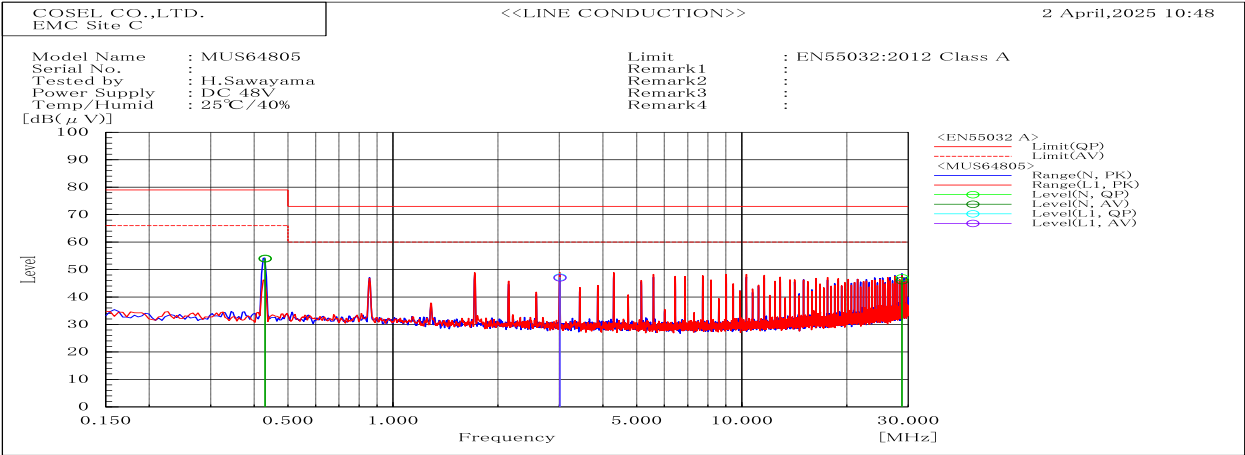
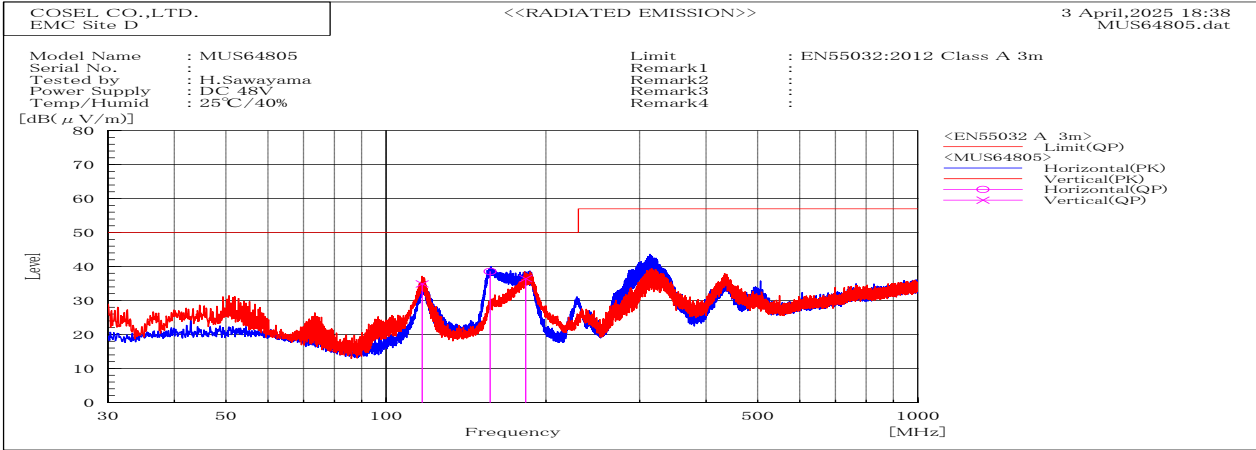


DATA SHEET		Date	02-Apr-25
Model	MUS64805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Sawayama



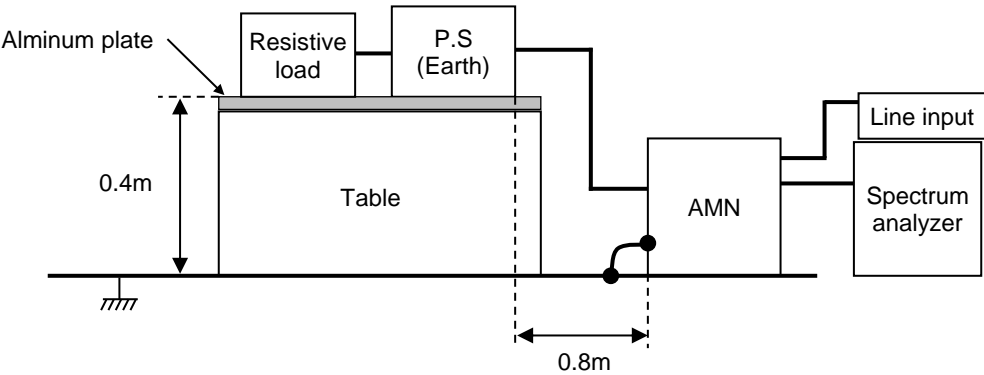
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
3.01	L1	47.2	47	73	60	25.8	13	Pass	
0.43	N	54.1	53.9	79	66	24.9	12.1	Pass	
28.813	N	47	46	73	60	26	14	Pass	



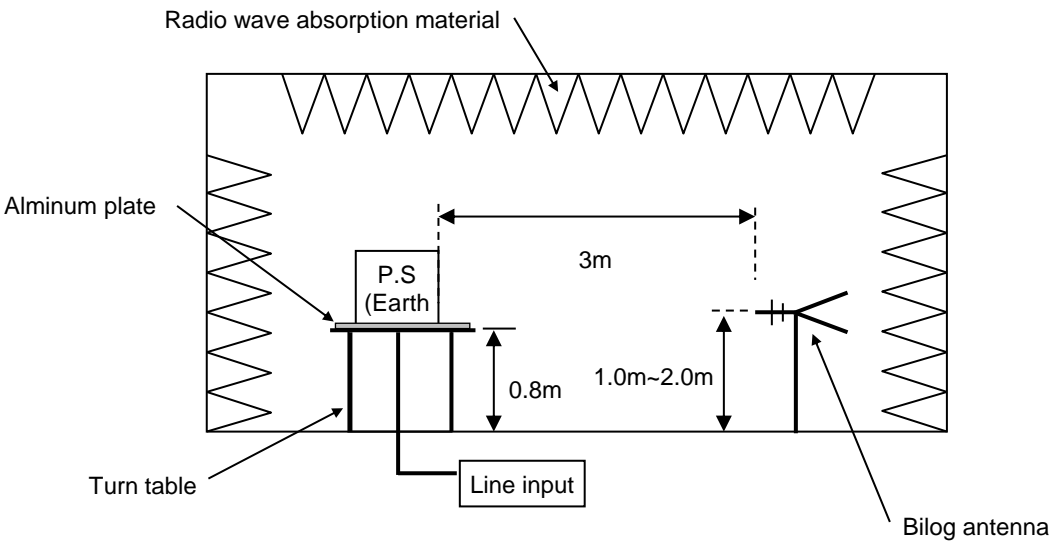
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
156.937	H	Stable	38.6	50	11.4	Pass	198.3	347.3	
183.173	V	Stable	36.4	50	13.6	Pass	100	242	
116.961	V	Stable	34.9	50	15.1	Pass	112.4	0	

DATA SHEET		Date	02-Apr-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Sawayama

1. Line conduction



2. Radiated emission



Conditions

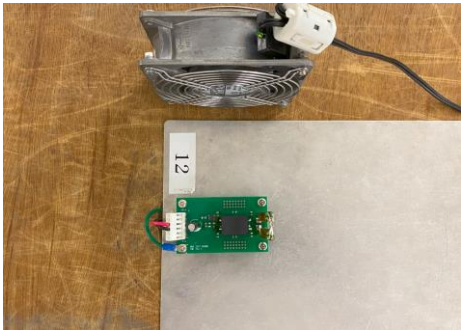
Test : EMI  
Model Name: MUS6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

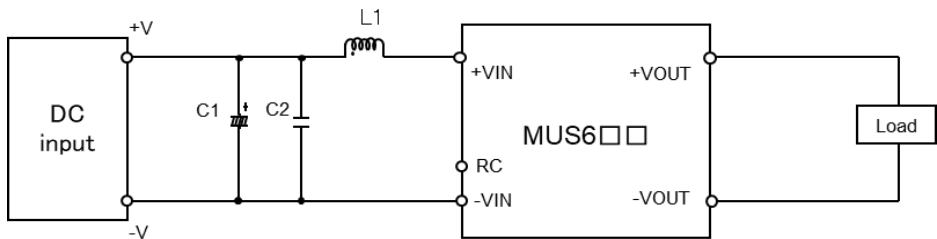


Fig.1 MUS6□□ Testing circuitry

C1 :	MUS605□	16V 220 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS612□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS624□	—	
	MUS648□	—	
C2 :	MUS605□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS612□	25V 10 $\mu$ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS624□	50V 4.7 $\mu$ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS648□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS605□	6500mA 1.5 $\mu$ H	Inductor(LQH5BPN1R5N38 MURATA MANUFACTURING)
	MUS612□	5000mA 2.2 $\mu$ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS624□	2600mA 10 $\mu$ H	Inductor(LQH5BPN100M38 MURATA MANUFACTURING)
	MUS648□	1600mA 22 $\mu$ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)